## Notice of References Cited Application/Control No. 10/824,434 Examiner Alvin H. Tan Applicant(s)/Patent Under Reexamination YOON ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,400,996	06-2002	Hoffberg et al.	700/83
*	В	US-6,563,430	05-2003	Kemink et al.	340/825.49
*	С	US-6,615,088	09-2003	Myer et al.	700/20
*	D	US-6,703,591	03-2004	Daum et al.	219/492
*	E	US-6,957,075	10-2005	Iverson, Vaughn S.	455/456.3
*	F	US-7,095,456	08-2006	Nakajima, Satoshi	348/734
*	G	US-2002/0105543	08-2002	Dong et al.	345/744
*	Н	US-2003/0059020	03-2003	Meyerson et al.	379/219
*	ı	US-2003/0083758	05-2003	Williamson, Charles G.	700/65
	J	US-			
	К	US-			
	٦	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.